

## High Speed IGBT Chip in NPT-technology

### **FEATURES:**

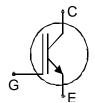
- low Eoff
- 600V NPT technology
- 100µm chip
- short circuit prove
- positive temperature coefficient
- easy paralleling

## This chip is used for:

• SGP30N60HS

## Applications:

- Welding
- PFC
- UPS



Chip Type	V <sub>CE</sub>	I <sub>Cn</sub>	Die Size	Package	Ordering Code
SIGC25T60UN	600V	30A	4.5 x 5.71 mm <sup>2</sup>	sawn on foil	Q67041-A4667-
313023100011	0000	307	4.5 × 5.7 1 11111	Sawii dii idii	A001

## **MECHANICAL PARAMETER:**

Raster size	4.5 x 5.71				
Area total / active	25.7 / 20.7				
Emitter pad size	2x( 2.18x1.58 )				
Gate pad size	1.08 x 0.68				
Thickness	100	μm			
Wafer size	150	mm			
Flat position	90	deg			
Max.possible chips per wafer	566				
Passivation frontside	Photoimide				
Emitter metallization	3200 nm Al Si 1%				
Collector metallization	1400 nm Ni Ag –system suitable for epoxy and soft solder die bonding				
Die bond	electrically conductive glue or solder				
Wire bond	AI, ≤500μm				
Reject Ink Dot Size	Ø 0.65mm; max 1.2mm				
Recommended Storage Environment	store in original container, in dry nitrogen, < 6 month at an ambient temperature of 23°C				



## **MAXIMUM RATINGS:**

Parameter	Symbol	Value	Unit
Collector-emitter voltage, T <sub>j</sub> =25 °C	V <sub>CE</sub>	600	V
DC collector current, limited by T <sub>jmax</sub>	I <sub>C</sub>	1)	Α
Pulsed collector current, t <sub>p</sub> limited by T <sub>jmax</sub>	I <sub>cpuls</sub>	90	Α
Gate emitter voltage	V <sub>GE</sub>	±20	V
Operating junction and storage temperature	$T_j$ , $T_{stg}$	-55 <b>+</b> 150	°C

<sup>1)</sup> depending on thermal properties of assembly

## **STATIC CHARACTERISTICS** (tested on chip), $T_i$ =25 °C, unless otherwise specified:

Parameter	Symbol	Conditions	Value			Unit
i didilictei		Conditions	min.	typ.	max.	
Collector-emitter breakdown voltage	V <sub>(BR)CES</sub>	$V_{GE}$ =0V, $I_{C}$ =500 $\mu$ A	600			
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	$V_{GE}$ =15V, $I_{C}$ =30A		2.8	3.15	V
Gate-emitter threshold voltage	$V_{\rm GE(th)}$	$I_C=300\mu A,\ V_{GE}=V_{CE}$	3	4	5	
Zero gate voltage collector current	I <sub>CES</sub>	V <sub>CE</sub> =600V, V <sub>GE</sub> =0V			2	μA
Gate-emitter leakage current	I <sub>GES</sub>	V <sub>CE</sub> =0V, V <sub>GE</sub> =20V			120	nA

## **DYNAMIC CHARACTERISTICS** (tested at component):

Parameter	Symbol	Conditions	Value			Unit
	Symbol		min.	typ.	max.	Oille
Input capacitance	Ciss	V <sub>CE</sub> =25V	-	1500		pF
Output capacitance	Coss	V <sub>GE</sub> =0 V   f=1 MHz	-	150		
Reverse transfer capacitance	C <sub>rss</sub>		-	92		

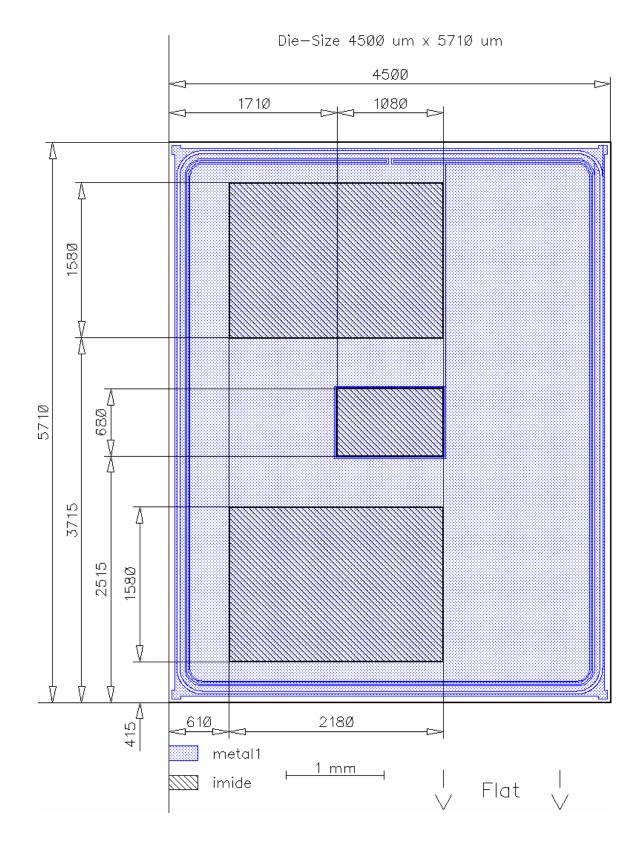
## **SWITCHING CHARACTERISTICS** (tested at component), Inductive Load:

Parameter	Symbol	Conditions 1)	Value			Unit
raiametei	Symbol		min.	typ.	max.	
Turn-on delay time	$t_{d(on)}$	T <sub>j</sub> =150°C	-	16		ns
Rise time	t <sub>r</sub>	$V_{\rm CC} = 400 \text{V}$	-	13		
Turn-off delay time	$t_{d(off)}$	$I_{C}$ =30A $V_{GE}$ =+15/0V	-	122		
Fall time	$t_{f}$	$R_{\rm G}$ =1.8 $\Omega$	-	29		

<sup>&</sup>lt;sup>1)</sup> values also influenced by parasitic L- and C- in measurement and package.



### **CHIP DRAWING:**





#### **FURTHER ELECTRICAL CHARACTERISTICS:**

This chip data sheet refers to the device data sheet SGP30N60HS Package :TO220

### **Description:**

AQL 0,65 for visual inspection according to failure catalog

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Test-Normen Villach/Prüffeld

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